# MTM86727

## Silicon N-channel MOS FET (FET) Silicon epitaxial planar type (SBD)

For DC-DC converter circuits For switching circuits

#### Overview

MTM86727 is the composite MOS FET (N-channel MOS FET and schottky barrier diode) that is highly suitable for DC-DC converter and other switching circuits.

#### ■ Features

• Built-in schottky barrier diode:  $V_R = 20 \text{ V}$ ,  $I_F = 800 \text{ mA}$ 

• Low ON resistance:  $R_{on} = 80 \text{ m}\Omega \text{ (V}_{GS} = 4.0 \text{ V)}$ 

• Low short-circuit input capacitance (common source): C<sub>iss</sub> = 280 pF

• Small package: WSSMini6-F1 (1.6 mm × 1.6 mm × 0.5 mm)

• Low drive voltage: 2.5 V drive

## ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter		Symbol	Rating	Unit	
FET	Drain-source surrender voltage	$V_{ m DSS}$	20	V	
	Gate-source surrender voltage	$V_{GSS}$	±10	VO	
	Drain current	$I_{\mathrm{D}}$	2.2	S A	
	Peak drain current	$I_{\mathrm{DP}}$	8.0	A	
	Channel temperature	$T_{ch}$	150	°C	
	Storage temperature	T <sub>stg</sub>	-55 to +150	°C	
	Reverse voltage	$V_R$	20	V	
	Forward current (Average)	$I_{F(AV)}$	800	mA	
SBD	Non-repetitive peak reverse surge voltage *1	$I_{FSM}$	3	A	
	Junction temperature	T <sub>j</sub>	125	°C	
	Storage temperature	T <sub>stg</sub>	-55 to +125	°C	
Overall	Total power dissipation *2	$P_{\mathrm{D}}$	540	mW	

Note) \*1: 50 Hz sine wave 1 cycle (Non-repetitive peak current)

\*2: Measuring on ceramic substrate at 40 mm  $\times$  38 mm  $\times$  0.2 mm  $P_D$  absolute maximum rating without a heat shink: 150 mW

#### ■ Package

• Code

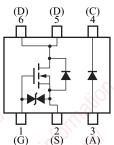
WSSMini6-F1

Pin Name

Gate
 Cathode
 Source
 Drain
 Anode
 Drain

■ Marking Symbo: JE

#### ■ Internal Connection



MTM86727

**Panasonic** 

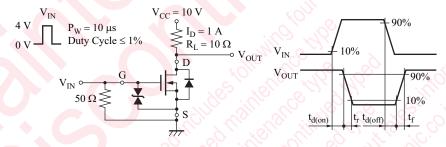
## ■ Electrical Characteristics $T_a = 25$ °C±3°C

#### • FET

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source surrender voltage	V <sub>DSS</sub>	$I_D = 1 \text{ mA}, V_{GS} = 0$	20			V
Drain-source cutoff current	$I_{DSS}$	$V_{DS} = 20 \text{ V}, V_{GS} = 0$			1.0	μΑ
Gate-source cutoff current	$I_{GSS}$	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0$			±10	μΑ
Gate threshold voltage	V <sub>TH</sub>	$I_D = 1.0 \text{ mA}, V_{DS} = 10 \text{ V}$	0.4	0.85	1.3	V
Drain-source ON resistance 1	R <sub>DS(on)</sub> 1	$I_D = 1 \text{ A}, V_{GS} = 4.0 \text{ V}$		80	105	mΩ
Drain-source ON resistance 2	R <sub>DS(on)</sub> 2	$I_D = 0.5 \text{ A}, V_{GS} = 2.5 \text{ V}$		100	150	mΩ
Forward transfer admittance	Y <sub>fs</sub>	$I_D = 1.0 \text{ A}, V_{DS} = 10 \text{ V}$	3.0			S
Short-circuit input capacitance (Common source)	C <sub>iss</sub>			280		pF
Short-circuit output capacitance (Common source)	C <sub>oss</sub>	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		18		pF
Reverse transfer capacitance (Common source)	C <sub>rss</sub>			17	ر ي.	pF
Turn-on delay time *	t <sub>d(on)</sub>			5		ns
Rise time *	t <sub>r</sub>	$V_{DD} = 10 \text{ V}, V_{GS} = 0 \text{ V to 4 V}, I_D = 1 \text{ A}$	25	8		ns
Turn-off delay time *	t <sub>d(off)</sub>	$V_{DD} = 6 \text{ V}, V_{GS} = 4 \text{ V to } 0 \text{ V}, I_D = 1 \text{ A}$	I I I I I I I I I I I I I I I I I I I	20		ns
Fall time *	$t_{\rm f}$	V <sub>DD</sub> - 0 V, V <sub>GS</sub> - 4 V to 0 V, I <sub>D</sub> - 1 A	3	18		ns

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

### 2. \*: Test circuit



### • SBD

Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Forward voltage		$V_{\rm F}$	$I_F = 800 \text{ mA}$	15		0.47	V
Reverse current	ce/V	$I_R$	$V_R = 20 \text{ V}$			80	μΑ

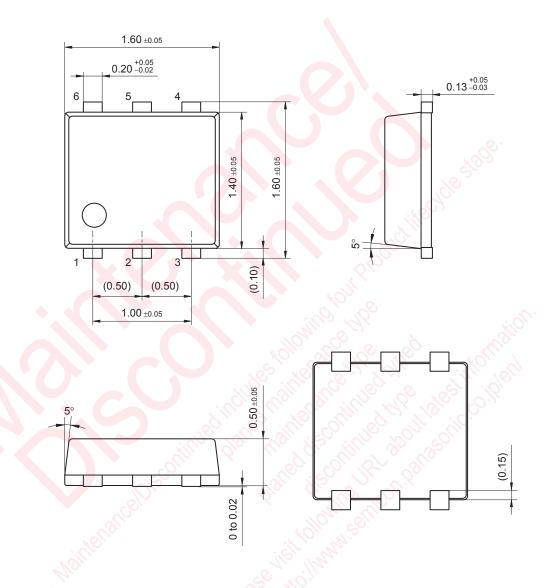
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 measuring methods for diodes.

2 SJF00086CED

Panasonic MTM86727

WSSMini6-F1

Unit: mm



# Request for your special attention and precautions in using the technical information and semiconductors described in this book

- (1) If any of the products or technical information described in this book is to be exported or provided to non-residents, the laws and regulations of the exporting country, especially, those with regard to security export control, must be observed.
- (2) The technical information described in this book is intended only to show the main characteristics and application circuit examples of the products. No license is granted in and to any intellectual property right or other right owned by Panasonic Corporation or any other company. Therefore, no responsibility is assumed by our company as to the infringement upon any such right owned by any other company which may arise as a result of the use of technical information described in this book.
- (3) The products described in this book are intended to be used for standard applications or general electronic equipment (such as office equipment, communications equipment, measuring instruments and household appliances).
  - Consult our sales staff in advance for information on the following applications:
  - Special applications (such as for airplanes, aerospace, automobiles, traffic control equipment, combustion equipment, life support systems and safety devices) in which exceptional quality and reliability are required, or if the failure or malfunction of the products may directly jeopardize life or harm the human body.
  - · Any applications other than the standard applications intended.
- (4) The products and product specifications described in this book are subject to change without notice for modification and/or improvement. At the final stage of your design, purchasing, or use of the products, therefore, ask for the most up-to-date Product Standards in advance to make sure that the latest specifications satisfy your requirements.
- (5) When designing your equipment, comply with the range of absolute maximum rating and the guaranteed operating conditions (operating power supply voltage and operating environment etc.). Especially, please be careful not to exceed the range of absolute maximum rating on the transient state, such as power-on, power-off and mode-switching. Otherwise, we will not be liable for any defect which may arise later in your equipment.
- Even when the products are used within the guaranteed values, take into the consideration of incidence of break down and failure mode, possible to occur to semiconductor products. Measures on the systems such as redundant design, arresting the spread of fire or preventing glitch are recommended in order to prevent physical injury, fire, social damages, for example, by using the products.
- (6) Comply with the instructions for use in order to prevent breakdown and characteristics change due to external factors (ESD, EOS, thermal stress and mechanical stress) at the time of handling, mounting or at customer's process. When using products for which damp-proof packing is required, satisfy the conditions, such as shelf life and the elapsed time since first opening the packages.
- (7) This book may be not reprinted or reproduced whether wholly or partially, without the prior written permission of our company.

20080805